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- Low Noise
- No External Components Required
- Replaces Chopper Amplifiers at a Lower Cost
- Single-Chip Monolithic Fabrication
- Wide Input Voltage Range 0 to ±14 V Typ
- Wide Supply Voltage Range ±3 V to ±18 V
- Essentially Equivalent to Fairchild µA714 Operational Amplifiers
- Direct Replacement for PMI OP07C and OP07D



NC-No internal connection

symbol



#### description

These devices represent a breakthrough in operational amplifier performance. Low offset and long-term stability are achieved by means of a low-noise, chopperless, bipolar-input-transistor amplifier circuit. For most applications, external components are not required for offset nulling and frequency compensation. The true differential input, with a wide input voltage range and outstanding common-mode rejection, provides maximum flexibility and performance in high-noise environments and in noninverting applications. Low bias currents and extremely high input impedances are maintained over the entire temperature range. The OP07 is unsurpassed for low-noise, high-accuracy amplification of very low-level signals.

These devices are characterized for operation from 0°C to 70°C.

	Viemov	PACKAGED	CHIP FORM					
TA	V <sub>IO</sub> max AT 25°C	SMALL OUTLINE (D)	PLASTIC DIP (P)	(Y)				
0°C to 70°C	150 μV	OP07CD OP07DD	OP07CP OP07DP	OP07Y				

#### **AVAILABLE OPTIONS**

The D package is available taped and reeled. Add the suffix R to the device type (e.g., OP07CDR). The chip form is tested at  $T_A = 25^{\circ}$ C.



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### **OP07Y** chip information

These chips, properly assembled, display characteristics similar to the OP07. Thermal compression or ultrasonic bonding may be used on the doped-aluminum bonding pads. Chips may be mounted with conductive epoxy or a gold-silicon preform.





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#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V <sub>CC+</sub> (see Note 1)	22 V
Supply voltage, V <sub>CC</sub>	
Differential input voltage (see Note 2)	±30 V
Input voltage, V <sub>I</sub> (either input, see Note 3)	±22 V
Duration of output short circuit (see Note 4)	unlimited
Continuous total dissipation at (or below) 25°C free-air temperature (see Note 5)	
Operating free-air temperature range, T <sub>A</sub>	0°C to 70°C
Storage temperature range	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

NOTES: 1. All voltage values, unless otherwise noted, are with respect to the midpoint between V<sub>CC+</sub> and V<sub>CC-</sub>.

- 2. Differential voltages are at IN+ with respect to IN-.
- 3. The magnitude of the input voltage must never exceed the magnitude of the supply voltage or 15 V, whichever is less.
- 4. The output may be shorted to ground or either power supply.
- 5. For operation above 64°C free-air temperature, derate the D package to 464 mW at 70°C at the rate of 5.8 mW/°C.

#### recommended operating conditions

			MAX	UNIT
Supply voltage, V <sub>CC±</sub>			±18	V
Common-mode input voltage, VIC	$V_{CC\pm} = \pm 15 V$	-13	13	V
Operating free-air temperature, T <sub>A</sub>			70	°C



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#### OP07C OP07D PARAMETER UNIT **TEST CONDITIONS<sup>†</sup>** TA MIN MAX TYP MAX TYP MIN 25°C 60 150 60 150 μV Vio Input offset voltage $V_{O} = 0$ , $R_S = 50 \Omega$ 0°C to 70°C 85 250 250 85 Temperature coefficient of input offset voltage $V_{O} = 0$ , $R_S = 50 \Omega$ 0°C to 70°C 0.5 1.8 0.7 2.5 μV/°C αγιο See Note 6 Long-term drift of input offset voltage 0.4 0.5 μV/mo $R_S = 20 k\Omega$ , Offset adjustment range See Figure 1 25°C $\pm 4$ $\pm 4$ m٧ 25°C 6 0.8 0.8 6 Input offset current 10 nA 8 8 0°C to 70°C 1.6 1.6 Temperature coefficient of input offset current $0^{\circ}$ C to $70^{\circ}$ C 12 50 12 50 pA/°C αιιο ±7 ±12 25°C ±1.8 ±2 Input bias current nA IВ $0^{\circ}$ C to $70^{\circ}$ C ±2.2 ±9 ±3 ±14 Temperature coefficient of input bias current 50 αIIB 0°C to 70°C 18 18 50 pA/°C 25°C ±14 ±14 ±13 ±13 VICR Common-mode input voltge range V 0°C to 70°C ±13 ±13.5 ±13 ±13.5 $R_{I} \ge 10 \ k\Omega$ ±12 ±13 ±12 $\pm 13$ $R_{I} \ge 2 \ k\Omega$ 25°C ±11.5 ±12.8 ±11.5 ±12.8 ۷ом Peak output voltage V $R_L \ge 1 \ k\Omega$ ±12 ±12 $R_{I} \ge 2 k\Omega$ 0°C to 70°C ±12.6 ±12.6 ±11 ±11 $V_{CC+} = \pm 3 V$ , $V_{O} = \pm 0.5 V_{0}$ 25°C 400 400 100 $R_L \geq 500 \; k\Omega$ Large-signal differential voltage amplification V/mV AVD 25°C 120 400 120 400 $V_{O} = \pm 10 V$ , $R_1 = 2 k\Omega$ 0°C to 70°C 100 400 100 400 B<sub>1</sub> Unity-gain bandwidth 25°C 0.4 0.6 0.4 0.6 MHz 25°C 8 33 7 31 MΩ Input resistance ri 25°C 100 120 94 110 Common-mode rejection ratio dB CMRR $V_{IC} = \pm 13 \text{ V}, \text{ Rs} = 50 \Omega$ $0^{\circ}C$ to $70^{\circ}C$ 120 94 106 97 7 25°C 32 7 32 $V_{CC\pm} = \pm 3 \text{ V to } \pm 18 \text{ V},$ ksvs Supply voltage sensitivity $(\Delta V_{IO}/\Delta V_{CC})$ μV/V $R_S = 50 \Omega$ $0^{\circ}C$ to $70^{\circ}C$ 10 51 10 51 $V_{O} = 0$ , No load 80 150 80 150 $V_{CC\pm} = \pm 3 \text{ V}, \quad V_{O} = 0,$ PD Power dissipation 25°C mW 4 8 8 4 No load

## electrical characteristics at specified free-air temperature, V<sub>CC</sub> $\pm$ = $\pm$ 15 V (unless otherwise noted)

<sup>†</sup> All characteristics are measured under open-loop conditions with zero common-mode input voltage unless otherwise noted.

NOTE 6: Since long-term drift cannot be measured on the individual devices prior to shipment, this specification is not intended to be a warranty. It is an engineering estimate of the averaged trend line of drift versus time over extended periods after the first thirty days of operation.

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## operating characteristics, V<sub>CC $\pm$ </sub> = ±15 V, T<sub>A</sub> = 25°C

PARAMETER		TEST	OP07C		OP07D			UNIT	
		CONDITIONS <sup>†</sup>	MIN	TYP	MAX	MIN	TYP	MAX	
	Equivalent input noise voltage	f = 10 Hz		10.5			10.5		nV/√ <del>Hz</del>
Vn		f = 100 Hz		10.2			10.3		
		f = 1 kHz		9.8			9.8		
V <sub>N(PP)</sub>	Peak-to-peak equivalent input noise voltage	f = 0.1 Hz to 10 Hz		0.38			0.38		μV
I <sub>n</sub>	Equivalent input noise current	f = 10 Hz		0.35			0.35		
		f = 100 Hz		0.15			0.15		pA/√Hz
		f = 1 kHz		0.13			0.13		
I <sub>N(PP)</sub>	Peak-to-peak equivalent input noise current	f = 0.1 Hz to 10 Hz		15			15		pА
SR	Slew rate	$R_L \ge 2 k\Omega$		0.3			0.3		V/µs

<sup>†</sup> All characteristics are measured under open-loop conditions with zero common-mode input voltage unless otherwise noted.

## electrical characteristics, V\_{CC\pm} = $\pm 15$ V, T\_A = 25°C (unless otherwise noted)

PARAMETER				OP07Y			
		TEST CONDITIONS <sup>†</sup>	MIN	TYP	MAX	UNIT	
VIO	Input offset voltage	R <sub>S</sub> = 50 Ω		60	150	μV	
	Long-term drift of input offset voltage	See Note 6		0.5		μV/mo	
	Offset adjustment range	$R_S = 20 k\Omega$ , See Figure 1		±4		mV	
IIO	Input offset current			0.8	6	nA	
IIB	Input bias current			±2	±12	nA	
VICR	Common-mode input voltage range		±13	±14		V	
	Peak output voltage	$R_L \le 10 \ k\Omega$	±12	±13			
∨ом		$R_L \le 2 k\Omega$	±11.5	±12.8		V	
		$R_L \le 1 \ k\Omega$		±12			
A	Large-signal differential voltage amplification	$V_{CC\pm} = \pm 3 \text{ V},  V_O = \pm 0.5 \text{ V},  R_L \le 500 \text{ k}\Omega$		400			
AVD		$V_{O} = \pm 10 \text{ V}, \qquad \text{R}_{L} = 2 \text{ k}\Omega$	120	400			
B <sub>1</sub>	Unity-gain bandwidth		0.4	0.6		MHz	
r <sub>i</sub>	Input resistance		7	31		MΩ	
CMRR	Common-mode input resistance	$V_{IC} = \pm 13 \text{ V},  R_S = 50 \Omega$	94	110		dB	
ksvs	Supply-voltage rejection ratio ( $\Delta V_{CC} / \Delta V_{IO}$ )	$V_{CC\pm} = \pm 3 \text{ V to } \pm 18 \text{ V}, \qquad R_{S} = 50 \Omega$		7	32	μV/V	
D		V <sub>O</sub> = 0, No load		80	150	Mo	
PD	Power dissipation	$V_{CC\pm} = \pm 3 V$ , $V_O = 0$ , No load		4	8	MΩ	

NOTE 6: Since long-term drift cannot be measured on the individual devices prior to shipment, this specification is not intended to be a warranty. It is an engineering estimate of the averaged trend line of drift versus time over extended periods after the first thirty days of operation.



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# operating characteristics, $V_{CC\pm}$ = $\pm 15$ V, $T_A$ = 25°C

PARAMETER		TEST CONDITIONS <sup>†</sup>	OP07Y			UNIT	
	PARAMETER	TEST CONDITIONS	MIN	ТҮР	MAX	UNIT	
		f = 10 Hz		10.5			
Vn	Equivalent input noise voltage	f = 1 kHz		10.3		nV/√Hz	
		f = 0.1 Hz to 10 Hz		9.8			
V <sub>N(PP)</sub>	Peak-to-peak equivalent input noise voltage	f = 0.1 Hz to 10 Hz		0.38		μV	
		f = 10 Hz		0.35			
In	Equivalent input noise current	f = 100 Hz		0.15		pA/√Hz	
		f = 1 kHz		0.13			
I <sub>N(PP)</sub>	Peak-to-peak equivalent input noise current	f = 0.1 Hz to 10 Hz		15		pА	
SR	Slew rate	$R_L = 2 k\Omega$		0.3		V/µs	

<sup>†</sup> All characteristics are measured under open-loop conditions with zero common-mode input voltage unless otherwise noted.

## **APPLICATION INFORMATION**



Figure 1. Input Offset Voltage Null Circuit



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